	74AC11379 QUAD D-TYPE FLIP-FLOP WITH CLOCK ENABLE SCAS104 - MARCH 1990 - REVISED APRIL 1993
 Contains Four Flip-Flops with Double-Rail	DW OR N PACKAGE
Outputs	(TOP VIEW)
 Clock Enable Latched to Avoid False Clocking 	$1\overline{Q} \begin{bmatrix} 1 & 20 \end{bmatrix} 1Q$ $2Q \begin{bmatrix} 2 & 19 \end{bmatrix} CLKEN$
 Applications Include: Buffer/Storage Registers, Shift Registers, Pattern Generators 	$2\overline{Q}$ $\begin{bmatrix} 2 & 19 \end{bmatrix}$ OLALIN $2\overline{Q}$ $\begin{bmatrix} 3 & 18 \end{bmatrix}$ 1D GND $\begin{bmatrix} 4 & 17 \end{bmatrix}$ 2D GND $\begin{bmatrix} 5 & 16 \end{bmatrix}$ V _{CC}
 Flow-Through Architecture Optimizes PCB	GND [6 15] V _{CC}
Layout	GND [7 14] 3D
 Center-Pin V_{CC} and GND Pin	3Q 8 13 4D
Configurations Minimize High-Speed	3Q 9 12 CLK
Switching Noise	4Q 10 11 4Q

- **EPIC**[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at • 125°C
- **Package Options Include Plastic** • **Small-Outline Packages and Standard Plastic 300-mil DIPs**

description

These circuits are positive-edge-triggered D-type flip-flops with a clock-enable input.

Information at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse if the clock-enable input (CLKEN) is low. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock input is at either the high or low level, the data (D) input signal has no effect at the output. The circuits are designed to prevent false clocking by transitions at the clock-enable (CLKEN) input.

The 74AC11379 is characterized for operation from – 40°C to 85°C.

(each flip-flop)									
IN	INPUTS								
CLKEN	CLK	D	Q	Q					
Н	Х	Х	Q ₀	\overline{Q}_0					
L	\uparrow	Н	н	L					
L	\uparrow	L	L	н					
Х	L	Х	Q ₀	\overline{Q}_0					

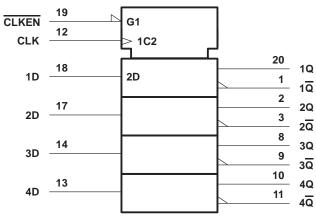
FUNCTION TABLE

EPIC is a trademark of Texas Instruments Incorporated.

74AC11379 QUAD D-TYPE FLIP-FLOP WITH CLOCK ENABLE

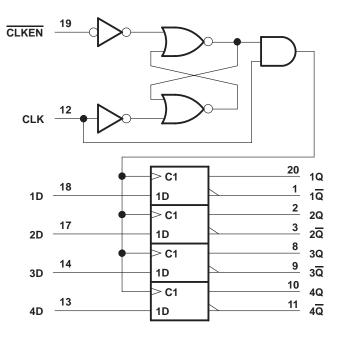
SCAS104 – MARCH 1990 – REVISED APRIL 1993

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

		• •	•	 •	,
Output voltage range, V_O (see Note 1) -0.5 V to $V_{CC} + 0.5 \text{ V}$ Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) $\pm 20 \text{ mA}$ Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) $\pm 50 \text{ mA}$ Continuous output current, I_O ($V_O = 0$ to V_{CC}) $\pm 50 \text{ mA}$ Continuous current through V_{CC} or GND pins $\pm 150 \text{ mA}$	Supply voltage range,	V _{CC}		 	–0.5 V to 7 V
$ \begin{array}{llllllllllllllllllllllllllllllllllll$	Input voltage range, V	(see Note 1))	 	-0.5 V to V _{CC} + 0.5 V
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)±50 mAContinuous output current, I_O ($V_O = 0$ to V_{CC})±50 mAContinuous current through V_{CC} or GND pins±150 mA	Output voltage range,	V _O (see Note	e 1)	 	-0.5 V to V _{CC} + 0.5 V
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$ $\pm 50 \text{ mA}$ Continuous current through V_{CC} or GND pins $\pm 150 \text{ mA}$	Input clamp current, I	K (VI < 0 or V	_I > V _{CC})	 	±20 mA
Continuous current through V _{CC} or GND pins ±150 mA	Output clamp current,	I_{OK} (V _O < 0 (or $V_O > V_{CC}$)	 	±50 mA
	Continuous output cur	rrent, I _O (V _O =	= 0 to V _{CC})	 	±50 mA
Storage temperature range	Continuous current th	rough V _{CC} or	GND pins .	 	±150 mA
	Storage temperature i	range		 	–65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



recommended operating conditions

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		3	5	5.5	V
		$V_{CC} = 3 V$	2.1			
VIH	High-level input voltage	$V_{CC} = 4.5 V$	3.15			V
		V _{CC} = 5.5 V	3.85			
		$V_{CC} = 3 V$			0.9	
VIL	Low-level input voltage	V _{CC} = 4.5 V			1.35	V
		$V_{CC} = 5.5 V$			1.65	
VI	Input voltage		0		VCC	V
VO	Output voltage		0		VCC	V
		V _{CC} = 3 V			-4	
ЮН	High-level output current	$V_{CC} = 4.5 V$			-24	mA
		V _{CC} = 5.5 V			-24	
		$V_{CC} = 3 V$			12	
lol	Low-level output current	V _{CC} = 4.5 V			24	mA
		V _{CC} = 5.5 V			24	
$\Delta t/\Delta v$	Input transition rise or fall rate		0		10	ns/V
TA	Operating free-air temperature		-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER		v	T/	A = 25°C	;	MIN		
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		
	l _{OH} = – 50 μA	4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
∨он	I _{OH} = - 4 mA		2.58			2.48		V
		4.5 V	3.94			3.8		
	I _{OL} = – 24 mA	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	l _{OL} = 50 μA	3 V			0.1		0.1	
		4.5 V			0.1		0.1	
		5.5 V			0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.44	V
		4.5 V			0.36		0.44	
	I _{OL} = 24 mA				0.36		0.44	
	I _{OL} = 75 mA [†]	5.5 V					1.65	
Ц	V _I = V _{CC} or GND	5.5 V			±0.1		±1	μΑ
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			8		80	μΑ
Ci	V _I = V _{CC} or GND	5 V		4				pF

⁺ Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



74AC11379 QUAD D-TYPE FLIP-FLOP WITH CLOCK ENABLE

SCAS104 – MARCH 1990 – REVISED APRIL 1993

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

			T _A = 2	25°C			
			MIN	MAX	MIN	MAX	UNIT
fclock	Clock frequency		0	90	0	90	MHz
tw	Pulse duration	CLK high or low	5.5		5.5		ns
		Data	7.5		7.5		
t _{su}	Setup time, before CLK1	CLKEN high or low	4.5		4.5		ns
		Data	0		0		
^t h	Hold time, after CLK↑	CLKEN inactive or active	0		0		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

				T _A = 25°C			
			MIN	MAX	MIN	MAX	UNIT
fclock	Clock frequency		0	100	0	100	MHz
tw	Pulse duration	CLK high or low	5		5		ns
		Data	5		5		
t _{su}	Setup time, before CLK1	CLKEN high or low	3		3		ns
	Held time offer OLKA	Data	0		0		
^t h	Hold time, after CLK↑	CLKEN inactive or active	0		0	ns	

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	Т	λ = 25°C	;			
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	UNIT
f _{max}			90	115		90		MHz
^t PLH		A	1.8	6.7	8.4	1.8	9.9	
^t PHL	CLK	Any Q or Q	3	9.5	13	3	14	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

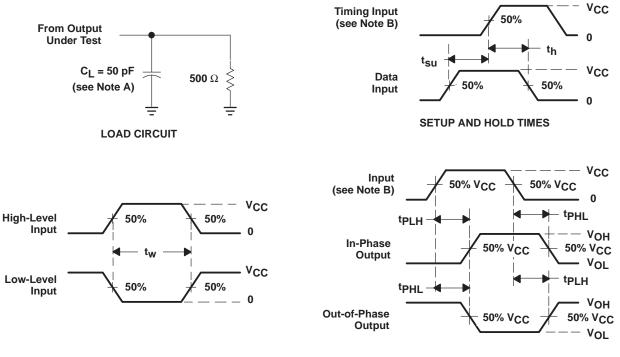
DADAMETER	FROM	то	Τ,	λ = 25°C	;			
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	UNIT
fmax			100	130		100		MHz
^t PLH		Amu O au 🗖	1.5	4.3	6	1.5	6.7	
^t PHL	CLK	Any Q or Q	2.6	6.2	9.1	2.6	10.3	ns

operating characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	38	pF



PARAMETER MEASUREMENT INFORMATION



PULSE DURATION

PROPAGATION DELAY TIMES

NOTES: A. CL includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
74AC11379DW	OBSOLETE	SOIC	DW	20	TBD	Call TI	Call TI

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details. TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
Low Power Wireless	www.ti.com/lpw	Telephony	www.ti.com/telephony
		Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments Post Office Box 655303 Dallas, Texas 75265

Copyright © 2007, Texas Instruments Incorporated